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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of **Embedded - Microprocessors**

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	2 Core, 32-Bit
Speed	1.5GHz
Co-Processors/DSP	Signal Processing; SPE, Security; SEC
RAM Controllers	DDR2, DDR3
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.5V, 1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	Cryptography, Random Number Generator
Package / Case	1023-BBGA, FCBGA
Supplier Device Package	1023-FCPBGA (33x33)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc8572elvjavne

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- Three inbound windows plus a configuration window on PCI Express
- Four inbound windows plus a default window on Serial RapidIO®
- Four outbound windows plus default translation for PCI Express
- Eight outbound windows plus default translation for Serial RapidIO with segmentation and sub-segmentation support
- Two 64-bit DDR2/DDR3 memory controllers
 - Programmable timing supporting DDR2 and DDR3 SDRAM
 - 64-bit data interface per controller
 - Four banks of memory supported, each up to 4 Gbytes, for a maximum of 16 Gbytes per controller
 - DRAM chip configurations from 64 Mbits to 4 Gbits with x8/x16 data ports
 - Full ECC support
 - Page mode support
 - Up to 32 simultaneous open pages for DDR2 or DDR3
 - Contiguous or discontiguous memory mapping
 - Cache line, page, bank, and super-bank interleaving between memory controllers
 - Read-modify-write support for RapidIO atomic increment, decrement, set, and clear transactions
 - Sleep mode support for self-refresh SDRAM
 - On-die termination support when using DDR2 or DDR3
 - Supports auto refreshing
 - On-the-fly power management using CKE signal
 - Registered DIMM support
 - Fast memory access through JTAG port
 - 1.8-V SSTL_1.8 compatible I/O
 - Support 1.5-V operation for DDR3. The detail is TBD pending on official release of appropriate industry specifications.
 - Support for battery-backed main memory
- Programmable interrupt controller (PIC)
 - Programming model is compliant with the OpenPIC architecture.
 - Supports 16 programmable interrupt and processor task priority levels
 - Supports 12 discrete external interrupts
 - Supports 4 message interrupts per processor with 32-bit messages
 - Supports connection of an external interrupt controller such as the 8259 programmable interrupt controller
 - Four global high resolution timers/counters per processor that can generate interrupts
 - Supports a variety of other internal interrupt sources



- Regular expression (regex) pattern matching
 - Built-in case insensitivity, wildcard support, no pattern explosion
 - Cross-packet pattern detection
 - Fast pattern database compilation and fast incremental updates
 - 16000 patterns, each up to 128 bytes in length
 - Patterns can be split into 256 sets, each of which can contain 16 subsets
- Stateful rule engine enables hardware execution of state-aware logic when a pattern is found
 - Useful for contextual searches, multi-pattern signatures, or for performing additional checks after a pattern is found
 - Capable of capturing and utilizing data from the data stream (such as LENGTH field) and using that information in subsequent pattern searches (for example, positive match only if pattern is detected within the number of bytes specified in the LENGTH field)
 - 8192 stateful rules
- Deflate engine
 - Supports decompression of DEFLATE compression format including zlib and gzip
 - Can work independently or in conjunction with the Pattern Matching Engine (that is decompressed data can be passed directly to the Pattern Matching Engine without further software involvement or memory copying)
- Two Table Lookup Units (TLU)
 - Hardware-based lookup engine offloads table searches from e500 cores
 - Longest prefix match, exact match, chained hash, and flat data table formats
 - Up to 32 tables, with each table up to 16M entries
 - 32-, 64-, 96-, or 128-bit keys
- Two I²C controllers
 - Two-wire interface
 - Multiple master support
 - Master or slave I²C mode support
 - On-chip digital filtering rejects spikes on the bus
- Boot sequencer
 - Optionally loads configuration data from serial ROM at reset the I²C interface
 - Can be used to initialize configuration registers and/or memory
 - Supports extended I²C addressing mode
 - Data integrity checked with preamble signature and CRC
- DUART
 - Two 4-wire interfaces (SIN, SOUT, $\overline{\text{RTS}}$, $\overline{\text{CTS}}$)
 - Programming model compatible with the original 16450 UART and the PC16550D
- Enhanced local bus controller (eLBC)



Electrical Characteristics

2.1.3 Output Driver Characteristics

Table 3 provides information on the characteristics of the output driver strengths.

Driver Type	Programmable Output Impedance (Ω)	Supply Voltage	Notes
Local bus interface utilities signals	25 35	BV _{DD} = 3.3 V BV _{DD} = 2.5 V	1
	45(default) 45(default) 125	BV _{DD} = 3.3 V BV _{DD} = 2.5 V BV _{DD} = 1.8 V	
DDR2 signal	18 36 (half strength mode)	GV _{DD} = 1.8 V	2
DDR3 signal	20 40 (half strength mode)	GV _{DD} = 1.5 V	2
eTSEC/10/100 signals	45	L/TV _{DD} = 2.5/3.3 V	—
DUART, system control, JTAG	45	OV _{DD} = 3.3 V	_
12C	150	OV _{DD} = 3.3 V	

Table 3. Output Drive Capability

Notes:

1. The drive strength of the local bus interface is determined by the configuration of the appropriate bits in PORIMPSCR.

2. The drive strength of the DDR2 or DDR3 interface in half-strength mode is at $T_i = 105^{\circ}C$ and at GV_{DD} (min).

2.2 Power Sequencing

The MPC8572E requires its power rails to be applied in a specific sequence to ensure proper device operation. These requirements are as follows for power up:

- 1. V_{DD}, AV_{DD}, BV_{DD}, LV_{DD}, OV_{DD}, SV_{DD}, SV_{DD}, SV_{DD}, XV_{DD}, XV_D
- 2. GV_{DD}

All supplies must be at their stable values within 50 ms.

Items on the same line have no ordering requirement with respect to one another. Items on separate lines must be ordered sequentially such that voltage rails on a previous step must reach 90% of their value before the voltage rails on the current step reach 10% of theirs.

To guarantee MCKE low during power-on reset, the above sequencing for GV_{DD} is required. If there is no concern about any of the DDR signals being in an indeterminate state during power-on reset, then the sequencing for GV_{DD} is not required.



PLL config input setup time with stable SYSCLK before HRESET negation	100	_	μs	
Input setup time for POR configs (other than PLL config) with respect to negation of HRESET	4		SYSCLKs	1
Input hold time for all POR configs (including PLL config) with respect to negation of HRESET	2	_	SYSCLKs	1
Maximum valid-to-high impedance time for actively driven POR configs with respect to negation of HRESET	—	5	SYSCLKs	1

Table 9. RESET Initialization Timing Specifications (continued)

Notes:

2. Reset assertion timing requirements for DDR3 DRAMs may differ.

Table 10 provides the PLL lock times.

Table	10.	PLL	Lock	Times
-------	-----	-----	------	-------

Parameter/Condition	Symbol	Min	Typical	Max
PLL lock times	_	100	μs	—
Local bus PLL	_	50	μs	_

6 DDR2 and DDR3 SDRAM Controller

This section describes the DC and AC electrical specifications for the DDR2 and DDR3 SDRAM controller interface of the MPC8572E. Note that the required $GV_{DD}(typ)$ voltage is 1.8Vor 1.5 V when interfacing to DDR2 or DDR3 SDRAM, respectively.

6.1 DDR2 and DDR3 SDRAM Interface DC Electrical Characteristics

Table 11 provides the recommended operating conditions for the DDR SDRAM controller of the MPC8572E when interfacing to DDR2 SDRAM.

Parameter/Condition	Symbol	Min	Мах	Unit	Notes
I/O supply voltage	GV _{DD}	1.71	1.89	V	1
I/O reference voltage	MV _{REF} n	$0.49 imes GV_{DD}$	$0.51 imes GV_{DD}$	V	2
I/O termination voltage	V _{TT}	MV _{REF} <i>n</i> – 0.04	$MV_{REF}n + 0.04$	V	3
Input high voltage	V _{IH}	$MV_{REF}n + 0.125$	GV _{DD} + 0.3	V	_
Input low voltage	V _{IL}	-0.3	MV _{REF} n – 0.125	V	_
Output leakage current	I _{OZ}	-50	50	μA	4
Output high current (V _{OUT} = 1.420 V)	I _{OH}	-13.4	_	mA	—

DDDO ODDAM Late	uface DO Electula	- I O le ave et eviletie e	$f_{a,m} = O(1 - (f_{a,m})) = A = O(1)$,
DURZ SURAW INTE	rtace DU Electric	al Unaracteristics	TOT (= V = (TVD) = T A V	

^{1.} SYSCLK is the primary clock input for the MPC8572E.



Ethernet: Enhanced Three-Speed Ethernet (eTSEC)

The Fast Ethernet Controller (FEC) operates in MII mode only, and complies with the AC and DC electrical characteristics specified in this chapter for MII. Note that if FEC is used, eTSEC 3 and 4 are only available in SGMII mode.

8.1.1 eTSEC DC Electrical Characteristics

All MII, GMII, RMII, and TBI drivers and receivers comply with the DC parametric attributes specified in Table 23 and Table 24. All RGMII, RTBI and FIFO drivers and receivers comply with the DC parametric attributes specified in Table 24. The RGMII and RTBI signals are based on a 2.5-V CMOS interface voltage as defined by JEDEC EIA/JESD8-5.

Parameter	Symbol	Min	Max	Unit	Notes
Supply voltage 3.3 V	LV _{DD} TV _{DD}	3.13	3.47	V	1, 2
Output high voltage $(LV_{DD}/TV_{DD} = Min, IOH = -4.0 mA)$	VOH	2.40	LV _{DD} /TV _{DD} + 0.3	V	—
Output low voltage $(LV_{DD}/TV_{DD} = Min, IOL = 4.0 mA)$	VOL	GND	0.50	V	—
Input high voltage	V _{IH}	2.0	$LV_{DD}/TV_{DD} + 0.3$	V	—
Input low voltage	V _{IL}	-0.3	0.90	V	—
Input high current $(V_{IN} = LV_{DD}, V_{IN} = TV_{DD})$	IIH	_	40	μΑ	1, 2,3
Input low current (V _{IN} = GND)	Ι _{ΙL}	-600	_	μA	3

Table 23.	GMII.	MII. RMII.	and TBI DC	Electrical	Characteristics
	. ,	,		Liootiioui	0114140101101100

Notes:

¹ LV_{DD} supports eTSECs 1 and 2.

 2 TV_{DD} supports eTSECs 3 and 4 or FEC.

 3 The symbol V_{IN}, in this case, represents the LV_{IN} and TV_{IN} symbols referenced in Table 1.

Table 24. MII, GMII, RMII, RGMII, TBI, RTBI, and FIFO DC Electrical Characteristics

Parameters	Symbol	Min	Мах	Unit	Notes
Supply voltage 2.5 V	LV _{DD/} TV _{DD}	2.37	2.63	V	1,2
Output high voltage ($LV_{DD}/TV_{DD} = Min, IOH = -1.0 mA$)	V _{OH}	2.00	$LV_{DD}/TV_{DD} + 0.3$	V	—
Output low voltage ($LV_{DD}/TV_{DD} = Min, I_{OL} = 1.0 mA$)	V _{OL}	GND – 0.3	0.40	V	—
Input high voltage	V _{IH}	1.70	$LV_{DD}/TV_{DD} + 0.3$	V	—
Input low voltage	V _{IL}	-0.3	0.70	V	—



Ethernet: Enhanced Three-Speed Ethernet (eTSEC)

Figure 14 shows the MII receive AC timing diagram.



Figure 14. MII Receive AC Timing Diagram

8.2.4 TBI AC Timing Specifications

This section describes the TBI transmit and receive AC timing specifications.

8.2.4.1 TBI Transmit AC Timing Specifications

Table 31 provides the TBI transmit AC timing specifications.

Table 31. TBI Transmit AC Timing Specifications

At recommended operating conditions with LV_{DD}/TV_{DD} of 2.5/ 3.3 V \pm 5%.

Parameter/Condition	Symbol ¹	Min	Тур	Max	Unit
TCG[9:0] setup time GTX_CLK going high	t _{TTKHDV}	2.0	_	—	ns
TCG[9:0] hold time from GTX_CLK going high	t _{TTKHDX}	1.0	—	—	ns
GTX_CLK rise (20%-80%)	t _{TTXR} ²	_	—	1.0	ns
GTX_CLK fall time (80%–20%)	t _{TTXF} ²	_	_	1.0	ns

Notes:

1. The symbols used for timing specifications herein follow the pattern of t_{(first two letters of functional block)(signal)(state)} for inputs and t_{(first two letters of functional block)(reference)(state)(signal)(state)} for outputs. For example, t_{TTKHDV} symbolizes the TBI transmit timing (TT) with respect to the time from t_{TTX} (K) going high (H) until the referenced data signals (D) reach the valid state (V) or setup time. Also, t_{TTKHDX} symbolizes the TBI transmit timing (TT) with respect to the time from t_{TTX} (K) going high (H) until the referenced data signals (D) reach the valid state (V) or setup time. Also, t_{TTKHDX} symbolizes the TBI transmit timing (TT) with respect to the time from t_{TTX} (K) going high (H) until the referenced data signals (D) reach the invalid state (X) or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{TTX} represents the TBI (T) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

2. Guaranteed by design.



Figure 17 shows the TBI receive the timing diagram.



Figure 17. TBI Single-Clock Mode Receive AC Timing Diagram

8.2.6 **RGMII and RTBI AC Timing Specifications**

Table 34 presents the RGMII and RTBI AC timing specifications.

Table 34. RGMII and RTBI AC Timing Specifications

At recommended operating conditions with $\text{LV}_{\text{DD}}/\text{TV}_{\text{DD}}$ of 2.5 V ± 5%.

Parameter/Condition	Symbol ¹	Min	Тур	Мах	Unit
Data to clock output skew (at transmitter)	t _{SKRGT}	-500	0	500	ps
Data to clock input skew (at receiver) ²	t _{SKRGT}	1.0	—	2.8	ns
Clock period ³	t _{RGT}	7.2	8.0	8.8	ns
Duty cycle for 10BASE-T and 100BASE-TX ^{3, 4}	t _{RGTH} /t _{RGT}	40	50	60	%
Rise time (20%–80%)	t _{rgtr}	—	—	0.75	ns
Fall time (20%–80%)	t _{RGTF}	_	_	0.75	ns

Notes:

- 1. Note that, in general, the clock reference symbol representation for this section is based on the symbols RGT to represent RGMII and RTBI timing. For example, the subscript of t_{RGT} represents the TBI (T) receive (RX) clock. Note also that the notation for rise (R) and fall (F) times follows the clock symbol that is being represented. For symbols representing skews, the subscript is skew (SK) followed by the clock that is being skewed (RGT).
- 2. This implies that PC board design requires clocks to be routed such that an additional trace delay of greater than 1.5 ns will be added to the associated clock signal.
- 3. For 10 and 100 Mbps, t_{RGT} scales to 400 ns ± 40 ns and 40 ns ± 4 ns, respectively.
- 4. Duty cycle may be stretched/shrunk during speed changes or while transitioning to a received packet's clock domains as long as the minimum duty cycle is not violated and stretching occurs for no more than three t_{RGT} of the lowest speed transitioned between.



described in Section 21.5, "Connection Recommendations," as long as such termination does not violate the desired POR configuration requirement on these pins, if applicable.

When operating in SGMII mode, the eTSEC EC_GTX_CLK125 clock is not required for this port. Instead, SerDes reference clock is required on SD2_REF_CLK and SD2_REF_CLK pins.

8.3.1 DC Requirements for SGMII SD2_REF_CLK and SD2_REF_CLK

The characteristics and DC requirements of the separate SerDes reference clock are described in Section 15, "High-Speed Serial Interfaces (HSSI)."

8.3.2 AC Requirements for SGMII SD2_REF_CLK and SD2_REF_CLK

Table 37 lists the SGMII SerDes reference clock AC requirements. Note that SD2_REF_CLK and SD2_REF_CLK are not intended to be used with, and should not be clocked by, a spread spectrum clock source.

Symbol	Parameter Description	Min	Typical	Max	Units	Notes
t _{REF}	REFCLK cycle time		10 (8)	_	ns	1
t _{REFCJ}	REFCLK cycle-to-cycle jitter. Difference in the period of any two adjacent REFCLK cycles		—	100	ps	_
t _{REFPJ}	Phase jitter. Deviation in edge location with respect to mean edge location	-50		50	ps	

Table 37. SD2_REF_CLK and SD2_REF_CLK AC Requirements

Note:

1.8 ns applies only when 125 MHz SerDes2 reference clock frequency is selected through cfg_srds_sgmii_refclk during POR.



Ethernet: Enhanced Three-Speed Ethernet (eTSEC)

8.3.3 SGMII Transmitter and Receiver DC Electrical Characteristics

Table 38 and Table 39 describe the SGMII SerDes transmitter and receiver AC-Coupled DC electrical characteristics. Transmitter DC characteristics are measured at the transmitter outputs (SD2_TX[n] and SD2_TX[n]) as depicted in Figure 23.

Parameter	Symbol	Min	Тур	Max	Unit	Notes
Supply Voltage	$\rm XV_{DD_SRDS2}$	1.045	1.1	1.155	V	—
Output high voltage	VOH	_	_	XV _{DD_SRDS2-Typ} /2 + V _{OD} _{-max} /2	mV	1
Output low voltage	VOL	XV _{DD_SRDS2-Typ} /2 - V _{OD} _{-max} /2	_	—	mV	1
Output ringing	V _{RING}	_	—	10	%	—
		359	550	791		Equalization setting: 1.0x
	V _{OD}	329	505	725		Equalization setting: 1.09x
Output differential voltage ^{2, 3, 5}		299	458	659		Equalization setting: 1.2x
		270	414	594	mV	Equalization setting: 1.33x
		239	367	527		Equalization setting: 1.5x
		210	322	462		Equalization setting: 1.71x
		180	275	395		Equalization setting: 2.0x
Output offset voltage	V _{OS}	473	550	628	mV	1, 4
Output impedance (single-ended)	R _O	40	_	60	Ω	—
Mismatch in a pair	ΔR_{O}	_	_	10	%	—
Change in V _{OD} between "0" and "1"	$\Delta V_{OD} $			25	mV	

Table 38. SGMII DC Transmitter Electrical Characteristics



At recommended operating conditions with OV_{DD} of 3.3 V ± 5%. All values refer to V_{IH} (min) and V_{IL} (max) levels (see Table 2).

Parameter	Symbol ¹	Min	Мах	Unit
Capacitive load for each bus line	Cb	—	400	pF

Notes:

NXP Semiconductors

- 1. The symbols used for timing specifications herein follow the pattern t_{(first two letters of functional block)(signal)(state)(reference)(state) for inputs and t_{(first two letters of functional block)(reference)(state)(signal)(state)} for outputs. For example, t_{I2DVKH} symbolizes I²C timing (I2) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time. Also, t_{I2SXKL} symbolizes I²C timing (I2) for the time that the data with respect to the t_{I2C} clock reference (K) going to the t_{I2C} clock reference (K) going to the t_{I2C} timing (I2) for the time that the data with respect to the t_{I2C} symbolizes I²C timing (I2) for the time that the data with respect to the t_{I2C} clock reference (K) going to the low (L) state or hold time. Also, t_{I2PVKH} symbolizes I²C timing (I2) for the time that the data with respect to the t_{I2C} clock reference (K) going to the t_{I2C} clock reference (K) going to the t_{I2C} timing (I2) for the time that the data with respect to the t_{I2C} clock reference (K) going to the t_{I2C} clock reference (K) going to the t_{I2C} timing (I2) for the time that the data with respect to the STOP condition (P) reaching the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time.}
- 2. As a transmitter, the MPC8572E provides a delay time of at least 300 ns for the SDA signal (referred to the VIHmin of the SCL signal) to bridge the undefined region of the falling edge of SCL to avoid unintended generation of START or STOP condition. When the MPC8572E acts as the I2C bus master while transmitting, the MPC8572E drives both SCL and SDA. As long as the load on SCL and SDA are balanced, the MPC8572E would not cause unintended generation of START or STOP condition. Therefore, the 300 ns SDA output delay time is not a concern. If, under some rare condition, the 300 ns SDA output delay time is required for the MPC8572E as transmitter, application note AN2919 referred to in note 4 below is recommended.
- 3. The maximum t_{I2OVKL} has only to be met if the device does not stretch the LOW period (t_{I2CL}) of the SCL signal.
- 4. The requirements for I²C frequency calculation must be followed. Refer to Freescale application note AN2919, *Determining the I²C Frequency Divider Ratio for SCL*.

Figure 40 provides the AC test load for the I^2C .



Figure 40. I²C AC Test Load

Figure 41 shows the AC timing diagram for the I^2C bus.



Figure 41. I²C Bus AC Timing Diagram



High-Speed Serial Interfaces (HSSI)

Figure 48 shows the SerDes reference clock connection reference circuits for HCSL type clock driver. It assumes that the DC levels of the clock driver chip is compatible with MPC8572E SerDes reference clock input's DC requirement.



Figure 48. DC-Coupled Differential Connection with HCSL Clock Driver (Reference Only)



High-Speed Serial Interfaces (HSSI)

clock driver chip manufacturer to verify whether this connection scheme is compatible with a particular clock driver chip.



Figure 50. AC-Coupled Differential Connection with LVPECL Clock Driver (Reference Only)

Figure 51 shows the SerDes reference clock connection reference circuits for a single-ended clock driver. It assumes the DC levels of the clock driver are compatible with MPC8572E SerDes reference clock input's DC requirement.



15.2.4 AC Requirements for SerDes Reference Clocks

The clock driver selected should provide a high quality reference clock with low phase noise and cycle-to-cycle jitter. Phase noise less than 100KHz can be tracked by the PLL and data recovery loops and





Symbol	Parameter	Min	Nominal	Max	Units	Comments
L _{RX-SKEW}	Total Skew		_	20	ns	Skew across all lanes on a Link. This includes variation in the length of SKP ordered set (for example, COM and one to five SKP Symbols) at the RX as well as any delay differences arising from the interconnect itself.

Notes:

- 1. No test load is necessarily associated with this value.
- 2. Specified at the measurement point and measured over any 250 consecutive UIs. The test load in Figure 57 should be used as the RX device when taking measurements (also refer to the Receiver compliance eye diagram shown in Figure 56). If the clocks to the RX and TX are not derived from the same reference clock, the TX UI recovered from 3500 consecutive UI must be used as a reference for the eye diagram.
- 3. A T_{RX-EYE} = 0.40 UI provides for a total sum of 0.60 UI deterministic and random jitter budget for the Transmitter and interconnect collected any 250 consecutive UIs. The T_{RX-EYE-MEDIAN-to-MAX-JITTER} specification ensures a jitter distribution in which the median and the maximum deviation from the median is less than half of the total. UI jitter budget collected over any 250 consecutive TX UIs. It should be noted that the median is not the same as the mean. The jitter median describes the point in time where the number of jitter points on either side is approximately equal as opposed to the averaged time value. If the clocks to the RX and TX are not derived from the same reference clock, the TX UI recovered from 3500 consecutive UI must be used as the reference for the eye diagram.
- 4. The Receiver input impedance shall result in a differential return loss greater than or equal to 15 dB with the D+ line biased to 300 mV and the D- line biased to -300 mV and a common mode return loss greater than or equal to 6 dB (no bias required) over a frequency range of 50 MHz to 1.25 GHz. This input impedance requirement applies to all valid input levels. The reference impedance for return loss measurements for is 50 ohms to ground for both the D+ and D- line (that is, as measured by a Vector Network Analyzer with 50 ohm probes see Figure 57). Note: that the series capacitors CTX is optional for the return loss measurement.
- 5. Impedance during all LTSSM states. When transitioning from a Fundamental Reset to Detect (the initial state of the LTSSM) there is a 5 ms transition time before Receiver termination values must be met on all un-configured Lanes of a Port.
- 6. The RX DC Common Mode Impedance that exists when no power is present or Fundamental Reset is asserted. This helps ensure that the Receiver Detect circuit does not falsely assume a Receiver is powered on when it is not. This term must be measured at 300 mV above the RX ground.
- 7. It is recommended that the recovered TX UI is calculated using all edges in the 3500 consecutive UI interval with a fit algorithm using a minimization merit function. Least squares and median deviation fits have worked well with experimental and simulated data.



Characteristic	Symbol	Range		Unit	Notos		
Characteristic	Symbol	Min	Мах	Unit	NOLES		
Differential Input Voltage	V _{IN}	200	1600	mV p-p	Measured at receiver		
Deterministic Jitter Tolerance	J _D	0.37	—	UI p-p	Measured at receiver		
Combined Deterministic and Random Jitter Tolerance	J _{DR}	0.55	_	UI p-p	Measured at receiver		
Total Jitter Tolerance ¹	J _T	0.65	_	UI p-p	Measured at receiver		
Multiple Input Skew	S _{MI}	_	24	ns	Skew at the receiver input between lanes of a multilane link		
Bit Error Rate	BER	_	10 ⁻¹²	_	_		
Unit Interval	UI	800	800	ps	+/– 100 ppm		

Table 72. Receiver AC Timing Specifications—1.25 GBaud

Note:

1. Total jitter is composed of three components, deterministic jitter, random jitter and single frequency sinusoidal jitter. The sinusoidal jitter may have any amplitude and frequency in the unshaded region of Figure 59. The sinusoidal jitter component is included to ensure margin for low frequency jitter, wander, noise, crosstalk and other variable system effects.

Characteristic	Symbol	Range		Unit	Netes	
Characteristic	Gymbol	Min	Мах	Unit	NOLES	
Differential Input Voltage	V _{IN}	200	1600	mV p-p	Measured at receiver	
Deterministic Jitter Tolerance	J _D	0.37	—	UI p-p	Measured at receiver	
Combined Deterministic and Random Jitter Tolerance	J _{DR}	0.55	—	UI p-p	Measured at receiver	
Total Jitter Tolerance ¹	J _T	0.65	_	UI p-p	Measured at receiver	
Multiple Input Skew	S _{MI}	_	24	ns	Skew at the receiver input between lanes of a multilane link	
Bit Error Rate	BER	—	10 ⁻¹²	—	—	
Unit Interval	UI	400	400	ps	+/– 100 ppm	

Table 73. Receiver AC Timing Specifications—2.5 GBaud

Note:

1. Total jitter is composed of three components, deterministic jitter, random jitter and single frequency sinusoidal jitter. The sinusoidal jitter may have any amplitude and frequency in the unshaded region of Figure 59. The sinusoidal jitter component is included to ensure margin for low frequency jitter, wander, noise, crosstalk and other variable system effects.







Figure 59. Single Frequency Sinusoidal Jitter Limits

17.7 Receiver Eye Diagrams

For each baud rate at which an LP-Serial receiver is specified to operate, the receiver shall meet the corresponding Bit Error Rate specification (Table 72, Table 73, and Table 74) when the eye pattern of the receiver test signal (exclusive of sinusoidal jitter) falls entirely within the unshaded portion of the Receiver Input Compliance Mask shown in Figure 60 with the parameters specified in Table 75. The eye pattern of the receiver test signal is measured at the input pins of the receiving device with the device replaced with a 100- Ω +/– 5% differential resistive load.



Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes
TSEC1_RX_DV/FIFO1_RX_D V/FIFO1_RXC[0]	Receive Data Valid	AL24	Ι	LV _{DD}	1
TSEC1_RX_ER/FIFO1_RX_E R/FIFO1_RXC[1]	Receive Data Error	AM29	I	LV _{DD}	1
TSEC1_TX_CLK/FIFO1_TX_C LK	Transmit Clock In	AB20	I	LV _{DD}	1
TSEC1_TX_EN/FIFO1_TX_EN /FIFO1_TXC[0]	Transmit Enable	AJ24	0	LV _{DD}	1, 22
TSEC1_TX_ER/FIFO1_TX_ER R/FIFO1_TXC[1]	Transmit Error	AK25	0	LV _{DD}	1, 5, 9
	Three-Speed Ethern	net Controller 2		•	
TSEC2_RXD[7:0]/FIFO2_RXD[7:0]/FIFO1_RXD[15:8]	Receive Data	AG22, AH20, AL22, AG20, AK21, AK22, AJ21, AK20	I	LV _{DD}	1
TSEC2_TXD[7:0]/FIFO2_TXD[7:0]/FIFO1_TXD[15:8]	Transmit Data	AH21, AF20, AC17, AF21, AD18, AF22, AE20, AB18	0	LV _{DD}	1, 5, 9, 24
TSEC2_COL/FIFO2_TX_FC	Collision Detect/Flow Control	AE19	Ι	LV _{DD}	1
TSEC2_CRS/FIFO2_RX_FC	Carrier Sense/Flow Control	AJ20	I/O	LV _{DD}	1, 16
TSEC2_GTX_CLK	Transmit Clock Out	AE18	0	LV _{DD}	—
TSEC2_RX_CLK/FIFO2_RX_C LK	Receive Clock	AL23	Ι	LV _{DD}	1
TSEC2_RX_DV/FIFO2_RX_D V/FIFO1_RXC[2]	Receive Data Valid	AJ22	I	LV _{DD}	1
TSEC2_RX_ER/FIFO2_RX_E R	Receive Data Error	AD19	Ι	LV _{DD}	1
TSEC2_TX_CLK/FIFO2_TX_C LK	Transmit Clock In	AC19	I	LV _{DD}	1
TSEC2_TX_EN/FIFO2_TX_EN /FIFO1_TXC[2]	Transmit Enable	AB19	0	LV _{DD}	1, 22
TSEC2_TX_ER/FIFO2_TX_ER R	Transmit Error	AB17	0	LV _{DD}	1, 5, 9
	Three-Speed Ether	net Controller 3			
TSEC3_TXD[3:0]/FEC_TXD[3: 0]/FIFO3_TXD[3:0]	Transmit Data	AG18, AG17, AH17, AH19	0	TV _{DD}	1, 5, 9
TSEC3_RXD[3:0]/FEC_RXD[3: 0]/FIFO3_RXD[3:0]	Receive Data	AG16, AK19, AD16, AJ19	I	TV _{DD}	1



Package Description

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes
SD2_RX[3:0]	Receive Data (negative)	AK31, AJ29, AF29, AE31	I	XV _{DD_SR} DS2	—
SD2_TX[3]	SGMII Tx Data eTSEC4	AH26	0	XV _{DD_SR} DS2	—
SD2_TX[2]	SGMII Tx Data eTSEC3	AG24	0	XV _{DD_SR} DS2	—
SD2_TX[1]	SGMII Tx Data eTSEC2	AE24	0	XV _{DD_SR} DS2	_
SD2_TX[0]	SGMII Tx Data eTSEC1	AD26	0	XV _{DD_SR} DS2	_
SD2_TX[3:0]	Transmit Data (negative)	AH27, AG25, AE25, AD27	0	XV _{DD_SR} DS2	—
SD2_PLL_TPD	PLL Test Point Digital	AH32	0	XV _{DD_SR} DS2	17
SD2_REF_CLK	PLL Reference Clock	AG32	I	XV _{DD_SR} DS2	—
SD2_REF_CLK	PLL Reference Clock Complement	AG31	I	XV _{DD_SR} DS2	—
Reserved	—	AF26, AF27	—	—	28
	General-Purpose	Input/Output			
GPINOUT[0:7]	General Purpose Input / Output	B27, A28, B31, A32, B30, A31, B28, B29	I/O	BV _{DD}	_
	System Co	ontrol			
HRESET	Hard Reset	AC31	I	OV _{DD}	_
HRESET_REQ	Hard Reset Request	L23	0	OV _{DD}	21
SRESET	Soft Reset	P24	I	OV _{DD}	
CKSTP_IN0	Checkstop In Processor 0	N26	I	OV _{DD}	
CKSTP_IN1	Checkstop In Processor 1	N25	I	OV _{DD}	_
CKSTP_OUT0	Checkstop Out Processor 0	U29	0	OV _{DD}	2, 4
CKSTP_OUT1	Checkstop Out Processor 1	T25	0	OV _{DD}	2, 4
	Debug	9			
TRIG_IN	Trigger In	P26	I	OV _{DD}	_
TRIG_OUT/READY_P0/QUIES	Trigger Out / Ready Processor 0/ Quiesce	P25	0	OV _{DD}	21
READY_P1	Ready Processor 1	N28	0	OV _{DD}	5, 9

Table 76. MPC8572E Pinout Listing (continued)



Package Description

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes
VDD	Core, L2, Logic Supply	L14, M13, M15, M17, N12, N14, N16, N20, N22, P11, P13, P15, P17, P19, P21, P23, R12, R14, R16, R18, R20, R22, T13, T15, T19, T21, T23, U12, U14, U18, U20, U22, V13, V15, V17, V19, V21, W12, W14, W16, W18, W20, W22, Y13, Y15, Y17, Y19, Y21, AA12, AA14, AA16, AA18, AA20, AB13		VDD	
SVDD_SRDS1	SerDes Core 1 Logic Supply (xcorevdd)	C31, D29, E28, E32, F30, G28, G31, H29, K30, L31, M29, N32, P30	_	_	_
SVDD_SRDS2	SerDes Core 2 Logic Supply (xcorevdd)	AD32, AF31, AG29, AJ32, AK29, AK30	_	—	_
XVDD_SRDS1	SerDes1 Transceiver Supply (xpadvdd)	C26, D24, E27, F25, G26, H24, J27, K25, L26, M24, N27	_	_	_
XVDD_SRDS2	SerDes2 Transceiver Supply (xpadvdd)	AD24, AD28, AE26, AF25, AG27, AH24, AJ26	_		_
AVDD_LBIU	Local Bus PLL Supply	A19	_	—	19
AVDD_DDR	DDR PLL Supply	AM20	_	—	19
AVDD_CORE0	CPU PLL Supply	B18	_		19
AVDD_CORE1	CPU PLL Supply	A17	_	—	19
AVDD_PLAT	Platform PLL Supply	AB32	_		19
AVDD_SRDS1	SerDes1 PLL Supply	J29	_	_	19
AVDD_SRDS2	SerDes2 PLL Supply	AH29	_	—	19
SENSEVDD	VDD Sensing Pin	N18	_	—	13
SENSEVSS	GND Sensing Pin	P18	—	—	13
	Analog Si	gnals			
MVREF1	SSTL_1.8 Reference Voltage	C16	I	GV _{DD} /2	_
MVREF2	SSTL_1.8 Reference Voltage	AM19	I	GV _{DD} /2	_

Table 76. MPC8572E Pinout Listing (continued)



System Design Information

logic does not interfere with normal chip operation. While the TAP controller can be forced to the reset state using only the TCK and TMS signals, generally systems assert TRST during the power-on reset flow. Simply tying TRST to HRESET is not practical because the JTAG interface is also used for accessing the common on-chip processor (COP), which implements the debug interface to the chip.

The COP function of these processors allow a remote computer system (typically, a PC with dedicated hardware and debugging software) to access and control the internal operations of the processor. The COP interface connects primarily through the JTAG port of the processor, with some additional status monitoring signals. The COP port requires the ability to independently assert HRESET or TRST to fully control the processor. If the target system has independent reset sources, such as voltage monitors, watchdog timers, power supply failures, or push-button switches, then the COP reset signals must be merged into these signals with logic.

The arrangement shown in Figure 66 allows the COP port to independently assert $\overline{\text{HRESET}}$ or $\overline{\text{TRST}}$, while ensuring that the target can drive $\overline{\text{HRESET}}$ as well.

The COP interface has a standard header, shown in Figure 65, for connection to the target system, and is based on the 0.025" square-post, 0.100" centered header assembly (often called a Berg header). The connector typically has pin 14 removed as a connector key.

The COP header adds many benefits such as breakpoints, watchpoints, register and memory examination/modification, and other standard debugger features. An inexpensive option can be to leave the COP header unpopulated until needed.

There is no standardized way to number the COP header; so emulator vendors have issued many different pin numbering schemes. Some COP headers are numbered top-to-bottom then left-to-right, while others use left-to-right then top-to-bottom. Still others number the pins counter-clockwise from pin 1 (as with an IC). Regardless of the numbering scheme, the signal placement recommended in Figure 65 is common to all known emulators.

21.9.1 Termination of Unused Signals

If the JTAG interface and COP header is not used, Freescale recommends the following connections:

- TRST should be tied to HRESET through a 0 k Ω isolation resistor so that it is asserted when the system reset signal (HRESET) is asserted, ensuring that the JTAG scan chain is initialized during the power-on reset flow. Freescale recommends that the COP header be designed into the system as shown in Figure 66. If this is not possible, the isolation resistor allows future access to TRST in case a JTAG interface may need to be wired onto the system in future debug situations.
- No pull-up/pull-down is required for TDI, TMS, TDO or TCK.



System Design Information



Notes:

- 1. The COP port and target board should be able to independently assert HRESET and TRST to the processor to fully control the processor as shown here.
- 2. Populate this with a 10 Ω resistor for short-circuit/current-limiting protection.
- 3. The KEY location (pin 14) is not physically present on the COP header.
- 4. Although pin 12 is defined as a No-Connect, some debug tools may use pin 12 as an additional GND pin for improved signal integrity.
- 5. This switch is included as a precaution for BSDL testing. The switch should be closed to position A during BSDL testing to avoid accidentally asserting the TRST line. If BSDL testing is not being performed, this switch should be closed to position B.
- 6. Asserting SRESET causes a machine check interrupt to the e500 cores.